

## Special Issue

# Quality Control and Product Monitoring in Manufacturing

### Message from the Guest Editors

Quality control and product monitoring play integral roles in modern manufacturing, ensuring consistent product quality, customer satisfaction, and regulatory adherence. This proposal outlines our intent to contribute to a special journal issue focused on these crucial aspects of manufacturing. Quality control encompasses systematic processes like statistical process control and Six Sigma methodologies. Product monitoring extends beyond the factory floor, involving real-time data collection and analysis using technologies such as IoT sensors, machine learning, and data analytics. These tools enable manufacturers to detect anomalies swiftly, improving product quality reducing waste and costs. In this Special Issue, we aim to explore recent advancements, best practices, and case studies in quality control and product monitoring across various manufacturing sectors. We will highlight how emerging technologies, data-driven insights, and collaborative strategies are reshaping these vital aspects of manufacturing, fostering innovation, sustainability, and global competitiveness.

### Guest Editors

Dr. Roham Sadeghi Tabar

Department of Industrial and Materials Sciences, Chalmers University of Technology, SE-412 96 Gothenburg, Sweden

Prof. Dr. Kristina Wärmeffjord

Department of Industrial and Materials Sciences, Chalmers University of Technology, SE-412 96 Gothenburg, Sweden

### Deadline for manuscript submissions

closed (20 July 2025)



## Applied Sciences

an Open Access Journal  
by MDPI

Impact Factor 2.5  
CiteScore 5.5



[mdpi.com/si/188070](https://mdpi.com/si/188070)

*Applied Sciences*  
Editorial Office  
MDPI, Grosspeteranlage 5  
4052 Basel, Switzerland  
Tel: +41 61 683 77 34  
[appls@mdpi.com](mailto:appls@mdpi.com)

[mdpi.com/journal/](https://mdpi.com/journal/)

[appls](https://appls.mdpi.com)





# Applied Sciences

---

an Open Access Journal  
by MDPI

---

Impact Factor 2.5  
CiteScore 5.5



[mdpi.com/journal/  
applsci](https://mdpi.com/journal/applsci)



## About the Journal

### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

---

### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo  
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,  
20133 Milano, Italy

---

### Author Benefits

#### Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

#### High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

#### Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering )